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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	400MHz
Co-Processors/DSP	Communications; QUICC Engine
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	740-LBGA
Supplier Device Package	740-TBGA (37.5x37.5)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8358vvagdga

wide range of protocols including ATM, Ethernet, HDLC, and POS. The QUICC Engine module's enhanced interworking eases the transition and reduces investment costs from ATM to IP based systems. The other major features include a dual DDR SDRAM memory controller for the MPC8360E, which allows equipment providers to partition system parameters and data in an extremely efficient way, such as using one 32-bit DDR memory controller for control plane processing and the other for data plane processing. The MPC8358E has a single DDR SDRAM memory controller. The MPC8360E/58E also offers a 32-bit PCI controller, a flexible local bus, and a dedicated security engine.

This figure shows the MPC8360E block diagram.

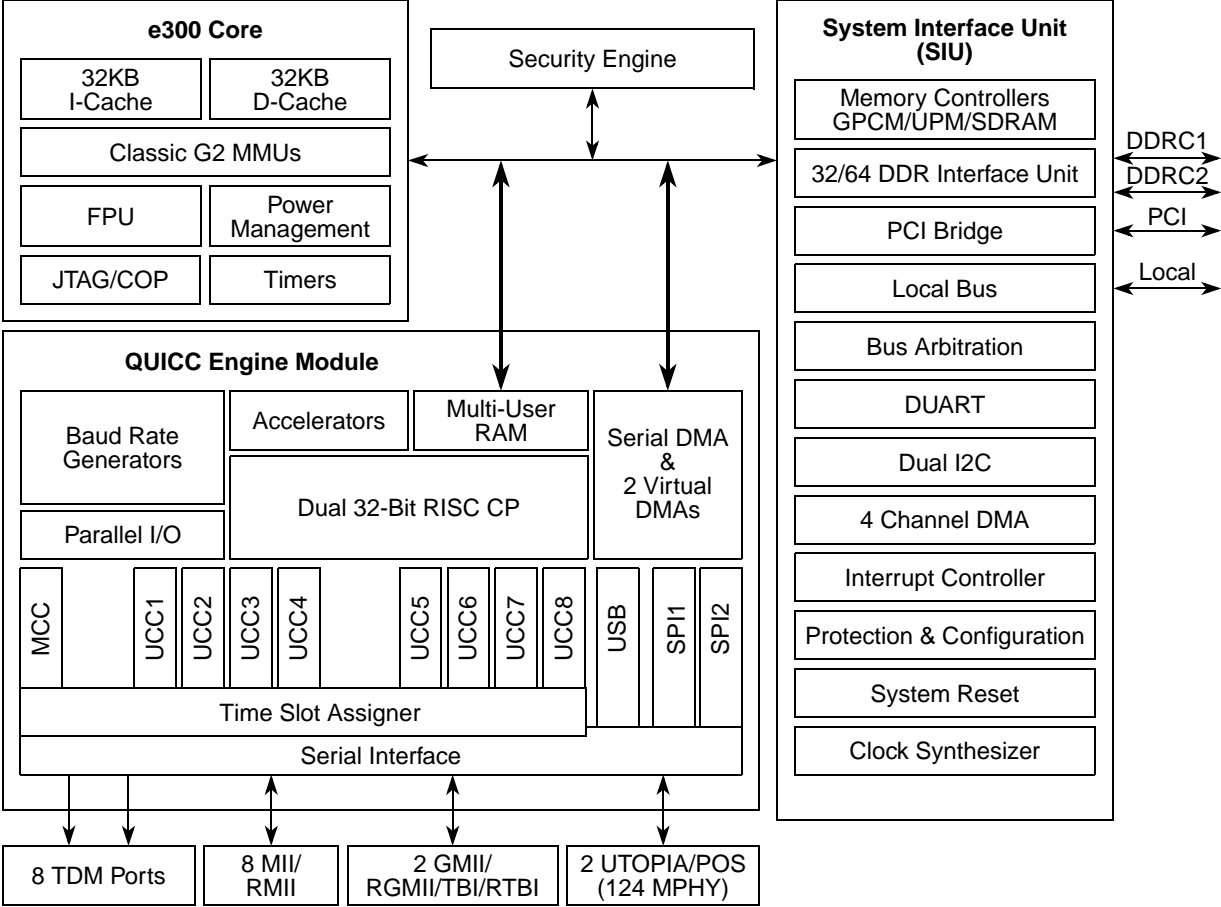


Figure 1. MPC8360E Block Diagram



- Programmable highest priority request
- Four groups of interrupts with programmable priority
- External and internal interrupts directed to communication processor
- Redirects interrupts to external $\overline{\text{INTA}}$ pin when in core disable mode
- Unique vector number for each interrupt source
- Dual industry-standard I²C interfaces
 - Two-wire interface
 - Multiple master support
 - Master or slave I²C mode support
 - On-chip digital filtering rejects spikes on the bus
 - System initialization data is optionally loaded from I²C-1 EPROM by boot sequencer embedded hardware
- DMA controller
 - Four independent virtual channels
 - Concurrent execution across multiple channels with programmable bandwidth control
 - All channels accessible by local core and remote PCI masters
 - Misaligned transfer capability
 - Data chaining and direct mode
 - Interrupt on completed segment and chain
 - DMA external handshake signals: $\overline{\text{DMA_DREQ}}[0:3]/\overline{\text{DMA_DACK}}[0:3]/\overline{\text{DMA_DONE}}[0:3]$. There is one set for each DMA channel. The pins are multiplexed to the parallel IO pins with other QE functions.
- DUART
 - Two 4-wire interfaces (RxD, TxD, RTS, CTS)
 - Programming model compatible with the original 16450 UART and the PC16550D
- System timers
 - Periodic interrupt timer
 - Real-time clock
 - Software watchdog timer
 - Eight general-purpose timers
- IEEE Std. 1149.1™-compliant, JTAG boundary scan
- Integrated PCI bus and SDRAM clock generation

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC8360E/58E. The device is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

This table shows the estimated typical I/O power dissipation for the device.

Table 6. Estimated Typical I/O Power Dissipation

Interface	Parameter	GV _{DD} (1.8 V)	GV _{DD} (2.5 V)	OV _{DD} (3.3 V)	LV _{DD} (3.3 V)	LV _{DD} (2.5 V)	Unit	Comments
DDR I/O 65% utilization R _s = 20 Ω R _t = 50 Ω 2 pairs of clocks	200 MHz, 1 × 32 bits	0.3	0.46	—	—	—	W	—
	200 MHz, 1 × 64 bits	0.4	0.58	—	—	—	W	—
	200 MHz, 2 × 32 bits	0.6	0.92	—	—	—	W	—
	266 MHz, 1 × 32 bits	0.35	0.56	—	—	—	W	—
	266 MHz, 1 × 64 bits	0.46	0.7	—	—	—	W	—
	266 MHz, 2 × 32 bits	0.7	1.11	—	—	—	W	—
	333 MHz, 1 × 32 bits	0.4	0.65	—	—	—	W	—
	333 MHz, 1 × 64 bits	0.53	0.82	—	—	—	W	—
Local Bus I/O Load = 25 pF 3 pairs of clocks	133 MHz, 32 bits	—	—	0.22	—	—	W	—
	83 MHz, 32 bits	—	—	0.14	—	—	W	—
	66 MHz, 32 bits	—	—	0.12	—	—	W	—
	50 MHz, 32 bits	—	—	0.09	—	—	W	—
PCI I/O Load = 30 pF	33 MHz, 32 bits	—	—	0.05	—	—	W	—
	66 MHz, 32 bits	—	—	0.07	—	—	W	—
10/100/1000 Ethernet I/O Load = 20 pF	MII or RMII	—	—	—	0.01	—	W	Multiply by number of interfaces used.
	GMII or TBI	—	—	—	0.04	—	W	
	RGMII or RTBI	—	—	—	—	0.04	W	
Other I/O	—	—	—	0.1	—	—	W	—

4 Clock Input Timing

This section provides the clock input DC and AC electrical characteristics for the MPC8360E/58E.

NOTE

The rise/fall time on QUICC Engine block input pins should not exceed 5 ns. This should be enforced especially on clock signals. Rise time refers to signal transitions from 10% to 90% of V_{DD}; fall time refers to transitions from 90% to 10% of V_{DD}.

Table 9. GTX_CLK125 AC Timing Specifications

 At recommended operating conditions with $V_{DD} = 2.5 \pm 0.125 \text{ mV} / 3.3 \text{ V} \pm 165 \text{ mV}$ (continued)

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
GTX_CLK rise and fall time $V_{DD} = 2.5 \text{ V}$ $V_{DD} = 3.3 \text{ V}$	t_{G125R}/t_{G125F}	—	—	0.75 1.0	ns	1
GTX_CLK125 duty cycle GMII & TBI 1000Base-T for RGMII & RTBI	t_{G125H}/t_{G125}	45 47	—	55 53	%	2
GTX_CLK125 jitter	—	—	—	± 150	ps	2

Notes:

- Rise and fall times for GTX_CLK125 are measured from 0.5 and 2.0 V for $V_{DD} = 2.5 \text{ V}$ and from 0.6 and 2.7 V for $V_{DD} = 3.3 \text{ V}$.
- GTX_CLK125 is used to generate the GTX clock for the UCC Ethernet transmitter with 2% degradation. The GTX_CLK125 duty cycle can be loosened from 47%/53% as long as the PHY device can tolerate the duty cycle generated by GTX_CLK. See Section 8.2.2, "MII AC Timing Specifications," Section 8.2.3, "RMII AC Timing Specifications," and Section 8.2.5, "RGMII and RTBI AC Timing Specifications" for the duty cycle for 10Base-T and 100Base-T reference clock.

5 RESET Initialization

This section describes the DC and AC electrical specifications for the reset initialization timing and electrical requirements of the MPC8360E/58E.

5.1 RESET DC Electrical Characteristics

This table provides the DC electrical characteristics for the RESET pins of the device.

Table 10. RESET Pins DC Electrical Characteristics ¹

Characteristic	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.0	$OV_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	-0.3	0.8	V
Input current	I_{IN}	—	—	± 10	μA
Output high voltage	V_{OH} ²	$I_{OH} = -8.0 \text{ mA}$	2.4	—	V
Output low voltage	V_{OL}	$I_{OL} = 8.0 \text{ mA}$	—	0.5	V
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.4	V

Notes:

- This table applies for pins $\overline{\text{PORESET}}$, $\overline{\text{HRESET}}$, $\overline{\text{SRESET}}$, and $\overline{\text{QUIESCE}}$.
- $\overline{\text{HRESET}}$ and $\overline{\text{SRESET}}$ are open drain pins, thus V_{OH} is not relevant for those pins.

8.2.1.2 GMII Receive AC Timing Specifications

This table provides the GMII receive AC timing specifications.

Table 28. GMII Receive AC Timing Specifications

At recommended operating conditions with V_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
RX_CLK clock period	t_{GRX}	—	8.0	—	ns	—
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	40	—	60	%	—
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns	—
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0.2	—	—	ns	2
RX_CLK clock rise time, (20% to 80%)	t_{GRXR}	—	—	1.0	ns	—
RX_CLK clock fall time, (80% to 20%)	t_{GRXF}	—	—	1.0	ns	—

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low state (L) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- In rev. 2.0 silicon, due to errata, t_{GRDXKH} minimum is 0.5 which is not compliant with the standard. Refer to Errata *QE_ENET18* in *Chip Errata for the MPC8360E, Rev. 1*.

This figure shows the GMII receive AC timing diagram.

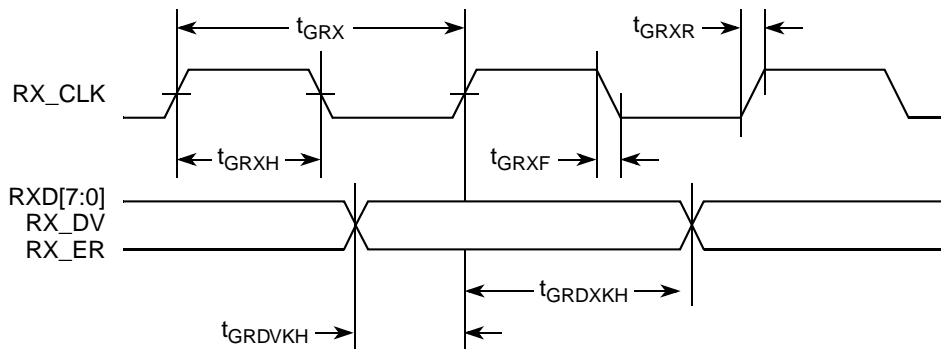


Figure 11. GMII Receive AC Timing Diagram

8.2.2.2 MII Receive AC Timing Specifications

This table provides the MII receive AC timing specifications.

Table 30. MII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise time, (20% to 80%)	t_{MRXR}	1.0	—	4.0	ns
RX_CLK clock fall time, (80% to 20%)	t_{MRXF}	1.0	—	4.0	ns

Note:

- The symbols used for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

This figure provides the AC test load.

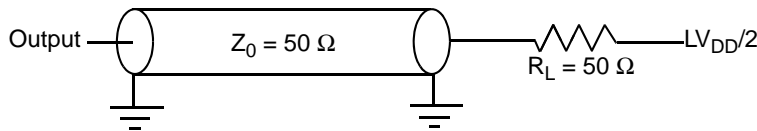


Figure 13. AC Test Load

This figure shows the MII receive AC timing diagram.

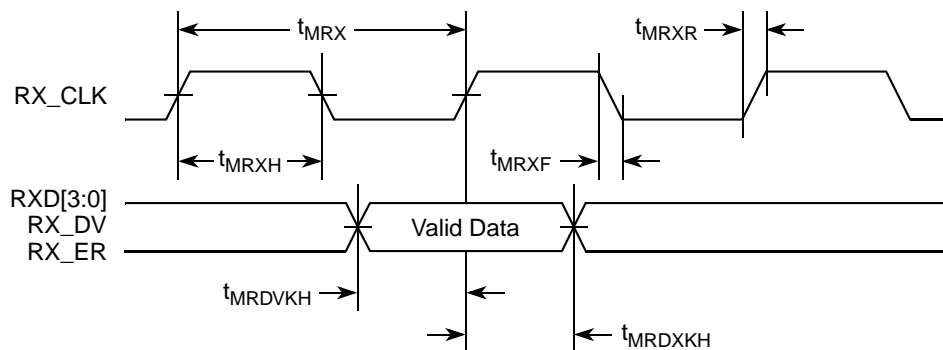


Figure 14. MII Receive AC Timing Diagram

8.2.3 RMII AC Timing Specifications

This section describes the RMII transmit and receive AC timing specifications.

8.2.3.1 RMII Transmit AC Timing Specifications

This table provides the RMII transmit AC timing specifications.

Table 31. RMII Transmit AC Timing Specifications

At recommended operating conditions with V_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
REF_CLK clock	t_{RMX}	—	20	—	ns
REF_CLK duty cycle	t_{RMXH}/t_{RMX}	35	—	65	%
REF_CLK to RMII data TXD[1:0], TX_EN delay	$t_{RMTKHDX}$ $t_{RMTKHDXV}$	2 —	—	— 10	ns
REF_CLK data clock rise time	t_{RMXR}	1.0	—	4.0	ns
REF_CLK data clock fall time	t_{RMXF}	1.0	—	4.0	ns

Note:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first three letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{RMTKHDX}$ symbolizes RMII transmit timing (RMT) for the time t_{RMX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{RMX} represents the RMII(RM) reference (X) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

This figure shows the RMII transmit AC timing diagram.

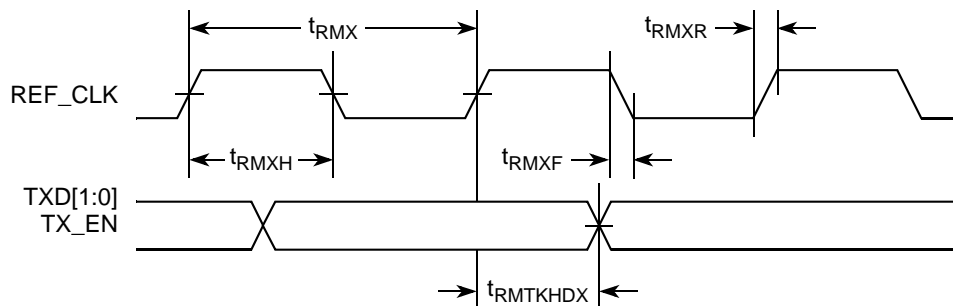


Figure 15. RMII Transmit AC Timing Diagram

8.2.3.2 RMII Receive AC Timing Specifications

This table provides the RMII receive AC timing specifications.

Table 32. RMII Receive AC Timing Specifications

At recommended operating conditions with V_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
REF_CLK clock period	t_{RMX}	—	20	—	ns
REF_CLK duty cycle	t_{RMXH}/t_{RMX}	35	—	65	%

8.2.4.1 TBI Transmit AC Timing Specifications

This table provides the TBI transmit AC timing specifications.

Table 33. TBI Transmit AC Timing Specifications

At recommended operating conditions with V_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
GTX_CLK clock period	t_{TTX}	—	8.0	—	ns	—
GTX_CLK duty cycle	t_{TTXH}/t_{TTX}	40	—	60	%	—
GTX_CLK to TBI data TCG[9:0] delay	t_{TTKHDV} t_{TTKHDV}	1.0 —	—	— 5.0	ns	3
GTX_CLK clock rise time, (20% to 80%)	t_{TTXR}	—	—	1.0	ns	—
GTX_CLK clock fall time, (80% to 20%)	t_{TTXF}	—	—	1.0	ns	—
GTX_CLK125 reference clock period	t_{G125}	—	8.0	—	ns	2
GTX_CLK125 reference clock duty cycle	t_{G125H}/t_{G125}	45	—	55	ns	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. This symbol is used to represent the external GTX_CLK125 and does not follow the original symbol naming convention.
3. In rev. 2.0 silicon, due to errata, t_{TTKHDV} minimum is 0.7 ns for UCC1. Refer to Errata *QE_ENET19* in *Chip Errata for the MPC8360E, Rev. 1*.

This figure shows the TBI transmit AC timing diagram.

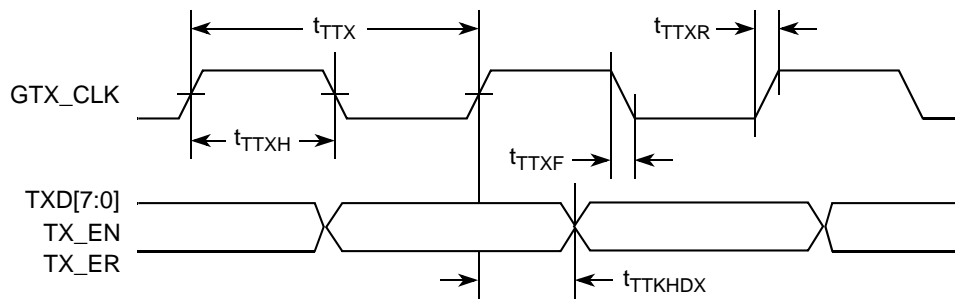


Figure 18. TBI Transmit AC Timing Diagram

8.2.4.2 TBI Receive AC Timing Specifications

This table provides the TBI receive AC timing specifications.

Table 34. TBI Receive AC Timing Specifications

At recommended operating conditions with V_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
PMA_RX_CLK clock period	t_{TRX}	—	16.0	—	ns	—
PMA_RX_CLK skew	t_{SKTRX}	7.5	—	8.5	ns	—
RX_CLK duty cycle	t_{TRXH}/t_{TRX}	40	—	60	%	—
RCG[9:0] setup time to rising PMA_RX_CLK	t_{TRDVKH}	2.5	—	—	ns	2
RCG[9:0] hold time to rising PMA_RX_CLK	t_{TRDXKH}	1.0	—	—	ns	2
RX_CLK clock rise time, $V_{IL}(\text{min})$ to $V_{IH}(\text{max})$	t_{TRXR}	0.7	—	2.4	ns	—
RX_CLK clock fall time, $V_{IH}(\text{max})$ to $V_{IL}(\text{min})$	t_{TRXF}	0.7	—	2.4	ns	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{TRDVKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{TRX} clock reference (K) going to the high (H) state or setup time. Also, t_{TRDXKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) went invalid (X) relative to the t_{TRX} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TRX} represents the TBI (T) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall). For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (TRX).
2. Setup and hold time of even numbered RCG are measured from riding edge of PMA_RX_CLK1. Setup and hold time of odd numbered RCG are measured from riding edge of PMA_RX_CLK0.

This figure shows the TBI receive AC timing diagram.

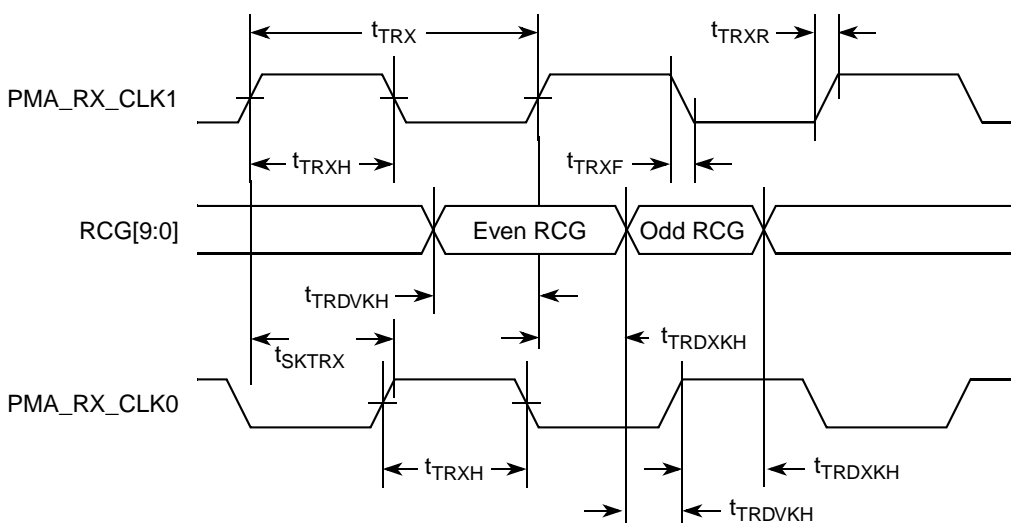


Figure 19. TBI Receive AC Timing Diagram

Table 40. Local Bus General Timing Parameters—DLL Enabled (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
LUPWAIT input hold from local bus clock	$t_{LBIXKH2}$	1.0	—	ns	3, 4
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT1}$	1.5	—	ns	5
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT2}$	3.0	—	ns	6
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT3}$	2.5	—	ns	7
Local bus clock to LALE rise	t_{LBKHLR}	—	4.5	ns	—
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	4.5	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	4.5	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	4.5	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	1.0	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	1.0	—	ns	3
Local bus clock to output high impedance for LAD/LDP	t_{LBKHOZ}	—	3.8	ns	8

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
- All timings are in reference to rising edge of LSYNC_IN.
- All signals are measured from $OV_{DD}/2$ of the rising edge of LSYNC_IN to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V signaling levels.
- Input timings are measured at the pin.
- $t_{LBOTOT1}$ should be used when RCWH[LALE] is not set and when the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
- $t_{LBOTOT2}$ should be used when RCWH[LALE] is set and when the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
- $t_{LBOTOT3}$ should be used when RCWH[LALE] is set and when the load on LALE output pin equals to the load on LAD output pins.
- For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

This table describes the general timing parameters of the local bus interface of the device.

Table 41. Local Bus General Timing Parameters—DLL Bypass Mode⁹

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	15	—	ns	2
Input setup to local bus clock	t_{LBIVKH}	7	—	ns	3, 4
Input hold from local bus clock	t_{LBIXKH}	1.0	—	ns	3, 4
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT1}$	1.5	—	ns	5
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT2}$	3	—	ns	6
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT3}$	2.5	—	ns	7

Table 41. Local Bus General Timing Parameters—DLL Bypass Mode⁹ (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus clock to output valid	t_{LBKHOV}	—	3	ns	3
Local bus clock to output high impedance for LAD/LDP	t_{LBKHOZ}	—	4	ns	8

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to falling edge of LCLK0 (for all outputs and for \overline{LGTA} and LUPWAIT inputs) or rising edge of LCLK0 (for all other inputs).
3. All signals are measured from $OV_{DD}/2$ of the rising/falling edge of LCLK0 to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. $t_{LBOTOT1}$ should be used when RCWH[LALE] is not set and when the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
6. $t_{LBOTOT2}$ should be used when RCWH[LALE] is set and when the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
7. $t_{LBOTOT3}$ should be used when RCWH[LALE] is set and when the load on LALE output pin equals to the load on LAD output pins.
8. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
9. DLL bypass mode is not recommended for use at frequencies above 66 MHz.

This figure provides the AC test load for the local bus.

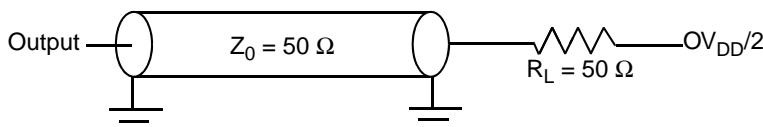


Figure 22. Local Bus C Test Load

11.2 I²C AC Electrical Specifications

This table provides the AC timing parameters for the I²C interface of the device.

Table 45. I²C AC Electrical Specifications

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 44).

Parameter	Symbol ¹	Min	Max	Unit	Note
SCL clock frequency	f_{I2C}	0	400	kHz	2
Low period of the SCL clock	t_{I2CL}	1.3	—	μs	—
High period of the SCL clock	t_{I2CH}	0.6	—	μs	—
Setup time for a repeated START condition	t_{I2SVKH}	0.6	—	μs	—
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL}	0.6	—	μs	—
Data setup time	t_{I2DVKH}	100	—	ns	3
Data hold time: CBUS compatible masters I ² C bus devices	t_{I2DXKL}	— 0 ²	— 0.9 ³	μs	—
Rise time of both SDA and SCL signals	t_{I2CR}	$20 + 0.1 C_B^4$	300	ns	—
Fall time of both SDA and SCL signals	t_{I2CF}	$20 + 0.1 C_B^4$	300	ns	—
Set-up time for STOP condition	t_{I2PVKH}	0.6	—	μs	—
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	μs	—
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	$0.1 \times OV_{DD}$	—	V	—
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	$0.2 \times OV_{DD}$	—	V	—

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- The device provides a hold time of at least 300 ns for the SDA signal (referred to the V_{IH} min of the SCL signal) to bridge the undefined region of the falling edge of SCL.
- The maximum t_{I2DVKH} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
- C_B = capacitance of one bus line in pF.

13.2 Timers AC Timing Specifications

This table provides the timer input and output AC timing specifications.

Table 50. Timers Input AC Timing Specifications¹

Characteristic	Symbol ²	Typ	Unit
Timers inputs—minimum pulse width	t_{TIWID}	20	ns

Notes:

1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of CLKIN. Timings are measured at the pin.
2. Timers inputs and outputs are asynchronous to any visible clock. Timers outputs should be synchronized before use by any external synchronous logic. Timers inputs are required to be valid for at least t_{TIWID} ns to ensure proper operation.

This figure provides the AC test load for the timers.

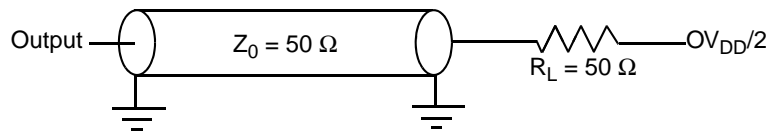


Figure 39. Timers AC Test Load

14 GPIO

This section describes the DC and AC electrical specifications for the GPIO of the MPC8360E/58E.

14.1 GPIO DC Electrical Characteristics

This table provides the DC electrical characteristics for the device GPIO.

Table 51. GPIO DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit	Notes
Output high voltage	V_{OH}	$I_{OH} = -6.0$ mA	2.4	—	V	1
Output low voltage	V_{OL}	$I_{OL} = 6.0$ mA	—	0.5	V	1
Output low voltage	V_{OL}	$I_{OL} = 3.2$ mA	—	0.4	V	1
Input high voltage	V_{IH}	—	2.0	$OV_{DD} + 0.3$	V	1
Input low voltage	V_{IL}	—	-0.3	0.8	V	—
Input current	I_{IN}	$0\text{ V} \leq V_{IN} \leq OV_{DD}$	—	± 10	μA	—

Note:

1. This specification applies when operating from 3.3-V supply.

Table 62. HDLC, BISYNC, and Transparent AC Timing Specifications¹ (continued)

Characteristic	Symbol ²	Min	Max	Unit
Outputs—Internal clock high impedance	t_{HIKHOX}	-0.5	5.5	ns
Outputs—External clock high impedance	t_{HEKHOX}	1	8	ns
Inputs—Internal clock input setup time	t_{HIIVKH}	8.5	—	ns
Inputs—External clock input setup time	t_{HEIVKH}	4	—	ns
Inputs—Internal clock input hold time	t_{HIIXKH}	1.4	—	ns
Inputs—External clock input hold time	t_{HEIXKH}	1	—	ns

Notes:

- Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
- The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{HIKHOX} symbolizes the outputs internal timing (HI) for the time t_{serial} memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).

Table 63. Synchronous UART AC Timing Specifications¹

Characteristic	Symbol ²	Min	Max	Unit
Outputs—Internal clock delay	t_{UAIKHOV}	0	11.3	ns
Outputs—External clock delay	t_{UAEKHOV}	1	14	ns
Outputs—Internal clock high impedance	t_{UAIKHOX}	0	11	ns
Outputs—External clock high impedance	t_{UAEKHOX}	1	14	ns
Inputs—Internal clock input setup time	t_{UAIIVKH}	6	—	ns
Inputs—External clock input setup time	t_{UAEIVKH}	8	—	ns
Inputs—Internal clock input hold time	t_{UAIIXKH}	1	—	ns
Inputs—External clock input hold time	t_{UAEIXKH}	1	—	ns

Notes:

- Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
- The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{HIKHOX} symbolizes the outputs internal timing (HI) for the time t_{serial} memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).

This figure provides the AC test load.

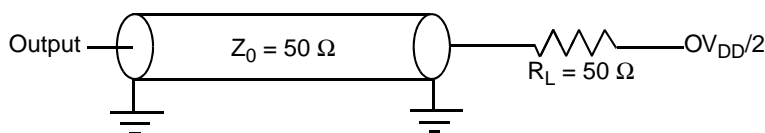

Figure 49. AC Test Load

Table 66. MPC8360E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI_DEVSEL/CE_PF[16]	E26	I/O	OV _{DD}	5
PCI_IDSEL/CE_PF[17]	F22	I/O	OV _{DD}	—
PCI_SERR/CE_PF[18]	B29	I/O	OV _{DD}	5
PCI_PERR/CE_PF[19]	A29	I/O	OV _{DD}	5
PCI_REQ[0]/CE_PF[20]	F19	I/O	LV _{DD2}	—
PCI_REQ[1]/CPCI_HS_ES/ CE_PF[21]	A21	I/O	LV _{DD2}	—
PCI_REQ[2]/CE_PF[22]	C21	I/O	LV _{DD2}	—
PCI_GNT[0]/CE_PF[23]	E20	I/O	LV _{DD2}	—
PCI_GNT[1]/CPCI1_HS_LED/ CE_PF[24]	B20	I/O	LV _{DD2}	—
PCI_GNT[2]/CPCI1_HS_ENUM/ CE_PF[25]	C20	I/O	LV _{DD2}	—
PCI_MODE	D36	I	OV _{DD}	—
M66EN/CE_PF[4]	B37	I/O	OV _{DD}	—
Local Bus Controller Interface				
LAD[0:31]	N32, N33, N35, N36, P37, P32, P34, R36, R35, R34, R33, T37, T35, T34, T33, U37, T32, U36, U34, V36, V35, W37, W35, V33, V32, W34, Y36, W32, AA37, Y33, AA35, AA34	I/O	OV _{DD}	—
LDP[0]/CKSTOP_OUT	AB37	I/O	OV _{DD}	—
LDP[1]/CKSTOP_IN	AB36	I/O	OV _{DD}	—
LDP[2]/LCS[6]	AB35	I/O	OV _{DD}	—
LDP[3]/LCS[7]	AA33	I/O	OV _{DD}	—
LA[27:31]	AC37, AA32, AC36, AC34, AD36	O	OV _{DD}	—
LCS[0:5]	AD33, AG37, AF34, AE33, AD32, AH37	O	OV _{DD}	—
LWE[0:3]/LSDDQM[0:3]/LBS[0:3]	AG35, AG34, AH36, AE32	O	OV _{DD}	—
LBCTL	AD35	O	OV _{DD}	—
LALE	M37	O	OV _{DD}	—
LGPL0/LSDA10/cfg_reset_source0	AB32	I/O	OV _{DD}	—
LGPL1/LSDWE/cfg_reset_source1	AE37	I/O	OV _{DD}	—
LGPL2/LSDRAS/LOE	AC33	O	OV _{DD}	—
LGPL3/LSDCAS/cfg_reset_source2	AD34	I/O	OV _{DD}	—
LGPL4/LGTA/LUPWAIT/LPBSE	AE35	I/O	OV _{DD}	—
LGPL5/cfg_clkin_div	AF36	I/O	OV _{DD}	—
LCKE	G36	O	OV _{DD}	—
LCLK[0]	J33	O	OV _{DD}	—
LCLK[1]/LCS[6]	J34	O	OV _{DD}	—

Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{IRQ}}[4:5]$	G33, G32	I/O	OV_{DD}	—
$\overline{\text{IRQ}}[6]/\overline{\text{LCS}}[6]/\overline{\text{CKSTOP_OUT}}$	E35	I/O	OV_{DD}	—
$\overline{\text{IRQ}}[7]/\overline{\text{LCS}}[7]/\overline{\text{CKSTOP_IN}}$	H36	I/O	OV_{DD}	—
DUART				
UART1_SOUT/M1SRCID[0]/M2SRCID[0]/LSRCID[0]	E32	O	OV_{DD}	—
UART1_SIN/M1SRCID[1]/M2SRCID[1]/LSRCID[1]	B34	I/O	OV_{DD}	—
$\overline{\text{UART1_CTS}}$ /M1SRCID[2]/M2SRCID[2]/LSRCID[2]	C34	I/O	OV_{DD}	—
$\overline{\text{UART1_RTS}}$ /M1SRCID[3]/M2SRCID[3]/LSRCID[3]	A35	O	OV_{DD}	—
I²C Interface				
IIC1_SDA	D34	I/O	OV_{DD}	2
IIC1_SCL	B35	I/O	OV_{DD}	2
IIC2_SDA	E33	I/O	OV_{DD}	2
IIC2_SCL	C35	I/O	OV_{DD}	2
QUICC Engine				
CE_PA[0]	F8	I/O	$\text{LV}_{\text{DD}0}$	—
CE_PA[1:2]	AH1, AG5	I/O	OV_{DD}	—
CE_PA[3:7]	F6, D4, C3, E5, A3	I/O	$\text{LV}_{\text{DD}0}$	—
CE_PA[8]	AG3	I/O	OV_{DD}	—
CE_PA[9:12]	F7, B3, E6, B4	I/O	$\text{LV}_{\text{DD}0}$	—
CE_PA[13:14]	AG1, AF6	I/O	OV_{DD}	—
CE_PA[15]	B2	I/O	$\text{LV}_{\text{DD}0}$	—
CE_PA[16]	AF4	I/O	OV_{DD}	—
CE_PA[17:21]	B16, A16, E17, A17, B17	I/O	$\text{LV}_{\text{DD}1}$	—
CE_PA[22]	AF3	I/O	OV_{DD}	—
CE_PA[23:26]	C18, D18, E18, A18	I/O	$\text{LV}_{\text{DD}1}$	—
CE_PA[27:28]	AF2, AE6	I/O	OV_{DD}	—
CE_PA[29]	B19	I/O	$\text{LV}_{\text{DD}1}$	—
CE_PA[30]	AE5	I/O	OV_{DD}	—
CE_PA[31]	F16	I/O	$\text{LV}_{\text{DD}1}$	—

Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
CE_PB[0:27]	AE2, AE1, AD5, AD3, AD2, AC6, AC5, AC4, AC2, AC1, AB5, AB4, AB3, AB1, AA6, AA4, AA2, Y6, Y4, Y3, Y2, Y1, W6, W5, W2, V5, V3, V2	I/O	OV _{DD}	—
CE_PC[0:1]	V1, U6	I/O	OV _{DD}	
CE_PC[2:3]	C16, A15	I/O	LV _{DD1}	—
CE_PC[4:6]	U4, U3, T6	I/O	OV _{DD}	—
CE_PC[7]	C19	I/O	LV _{DD2}	—
CE_PC[8:9]	A4, C5	I/O	LV _{DD0}	—
CE_PC[10:30]	T5, T4, T2, T1, R5, R3, R1, C11, D12, F13, B10, C10, E12, A9, B8, D10, A14, E15, B14, D15, AH2	I/O	OV _{DD}	—
CE_PD[0:27]	E11, D9, C8, F11, A7, E9, C7, A6, F10, B6, D7, E8, B5, A5, C2, E4, F5, B1, D2, G5, D1, E2, H6, F3, E1, F2, G3, H4	I/O	OV _{DD}	—
CE_PE[0:31]	K3, J2, F1, G2, J5, H3, G1, H2, K6, J3, K5, K4, L6, P6, P4, P3, P1, N4, N5, N2, N1, M2, M3, M5, M6, L1, L2, L4, E14, C13, C14, B13	I/O	OV _{DD}	—
CE_PF[0:3]	F14, D13, A12, A11	I/O	OV _{DD}	—
Clocks				
PCI_CLK_OUT[0]/CE_PF[26]	B22	I/O	LV _{DD2}	—
PCI_CLK_OUT[1:2]/CE_PF[27:28]	D22, A23	I/O	OV _{DD}	—
CLKIN	E37	I	OV _{DD}	—
PCI_CLOCK/PCI_SYNC_IN	M36	I	OV _{DD}	—
PCI_SYNC_OUT/CE_PF[29]	D37	I/O	OV _{DD}	3
JTAG				
TCK	K33	I	OV _{DD}	—
TDI	K34	I	OV _{DD}	4
TDO	H37	O	OV _{DD}	3
TMS	J36	I	OV _{DD}	4
$\overline{\text{TRST}}$	L32	I	OV _{DD}	4
Test				
TEST	L35	I	OV _{DD}	7
$\overline{\text{TEST_SEL}}$	AU34	I	GV _{DD}	10
PMC				
$\overline{\text{QUIESCE}}$	B36	O	OV _{DD}	—
System Control				

Example 1. Sample Table Use

Index	SPMF	CORE PLL	CEPMF	CEPDF	Input Clock (MHz)	CSB Freq (MHz)	Core Freq (MHz)	QUICC Engine Freq (MHz)	400 (MHz)	533 (MHz)	667 (MHz)
A	1000	0000011	01001	0	33	266	400	300	∞	∞	∞
B	0100	0000100	00110	0	66	266	533	400	∞	∞	∞

- Example A.** To configure the device with CSB clock rate of 266 MHz, core rate of 400 MHz, and QUICC Engine clock rate 300 MHz while the input clock rate is 33 MHz. Conf No. 's10' and 'c1' are selected from [Table 76](#). SPMF is 1000, CORPLL is 0000011, CEPMF is 01001, and CEPDF is 0.
- Example B.** To configure the device with CSBCSB clock rate of 266 MHz, core rate of 533 MHz and QUICC Engine clock rate 400 MHz while the input clock rate is 66 MHz. Conf No. 's5h' and 'c2h' are selected from [Table 76](#). SPMF is 0100, CORPLL is 0000100, CEPMF is 00110, and CEPDF is 0.

22 Thermal

This section describes the thermal specifications of the MPC8360E/58E.

22.1 Thermal Characteristics

This table provides the package thermal characteristics for the 37.5 mm × 37.5 mm 740-TBGA package.

Table 77. Package Thermal Characteristics for the TBGA Package

Characteristic	Symbol	Value	Unit	Notes
Junction-to-ambient natural convection on single-layer board (1s)	$R_{\theta JA}$	15	°C/W	1, 2
Junction-to-ambient natural convection on four-layer board (2s2p)	$R_{\theta JA}$	11	°C/W	1, 3
Junction-to-ambient (@ 1 m/s) on single-layer board (1s)	$R_{\theta JMA}$	10	°C/W	1, 3
Junction-to-ambient (@ 1 m/s) on four-layer board (2s2p)	$R_{\theta JMA}$	8	°C/W	1, 3
Junction-to-ambient (@ 2 m/s) on single-layer board (1s)	$R_{\theta JMA}$	9	°C/W	1, 3
Junction-to-ambient (@ 2 m/s) on four-layer board (2s2p)	$R_{\theta JMA}$	7	°C/W	1, 3
Junction-to-board thermal	$R_{\theta JB}$	4.5	°C/W	4
Junction-to-case thermal	$R_{\theta JC}$	1.1	°C/W	5

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

T_J = junction temperature ($^{\circ}\text{C}$)

T_B = board temperature at the package perimeter ($^{\circ}\text{C}$)

$R_{\theta JA}$ = junction to board thermal resistance ($^{\circ}\text{C}/\text{W}$) per JESD51-8

P_D = power dissipation in the package (W)

When the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. The application board should be similar to the thermal test condition: the component is soldered to a board with internal planes.

22.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, the Thermal Characterization Parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_J = junction temperature ($^{\circ}\text{C}$)

T_T = thermocouple temperature on top of package ($^{\circ}\text{C}$)

Ψ_{JT} = junction-to-ambient thermal resistance ($^{\circ}\text{C}/\text{W}$)

P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

22.2.4 Heat Sinks and Junction-to-Ambient Thermal Resistance

In some application environments, a heat sink is required to provide the necessary thermal management of the device. When a heat sink is used, the thermal resistance is expressed as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance ($^{\circ}\text{C}/\text{W}$)

$R_{\theta JC}$ = junction-to-case thermal resistance ($^{\circ}\text{C}/\text{W}$)

$R_{\theta CA}$ = case-to-ambient thermal resistance ($^{\circ}\text{C}/\text{W}$)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the airflow around the device, the interface material, the mounting arrangement on printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device.

To illustrate the thermal performance of the devices with heat sinks, the thermal performance has been simulated with a few commercially available heat sinks. The heat sink choice is determined by the application environment (temperature, airflow, adjacent component power dissipation) and the physical space available. Because there is not a standard application environment, a standard heat sink is not required.

Table 81. SVR Settings (continued)

Device	Package	SVR (Rev. 2.0)	SVR (Rev. 2.1)
MPC8358E	TBGA	0x804A_0020	0x804A_0021
MPC8358	TBGA	0x804B_0020	0x804B_0021

25 Document Revision History

This table provides a revision history for this document.

Table 82. Revision History

Rev. Number	Date	Substantive Change(s)
5	09/2011	<ul style="list-style-type: none"> • Section 2.2.1, “Power-Up Sequencing”, added the current limitation “3A to 5A” for the excessive current. • Section 2.1.2, “Power Supply Voltage Specification, Updated the Characteristic for TBGA (MPC8358 & MPC8360 Device) with specific frequency for Core and PLL voltages. • Added table footnote 3 to Table 2. • Applied table footnotes 1 and 2 to Table 10. • Removed table footnotes from Table 19. • Applied table footnote 8 to the last row of Table 40. • Applied table footnotes 8 and 9 to Table 41. • Applied table footnotes 2 and 3 to Table 45. • Removed table footnotes from Table 46. • Applied table footnote to last three rows of Table 65.
4	01/2011	<ul style="list-style-type: none"> • Updated references to the LCRR register throughout • Removed references to DDR DLL mode in Section 6.2.2, “DDR and DDR2 SDRAM Output AC Timing Specifications.” • Changed “Junction-to-Case” to “Junction-to-Ambient” in Section 22.2.4, “Heat Sinks and Junction-to-Ambient Thermal Resistance,” and Table 78, “Heat Sinks and Junction-to-Ambient Thermal Resistance of TBGA Package,” titles.